



Progress on ICECAL prototypes and chip tests

Upgrade of the front end electronics of the LHCb
calorimeter

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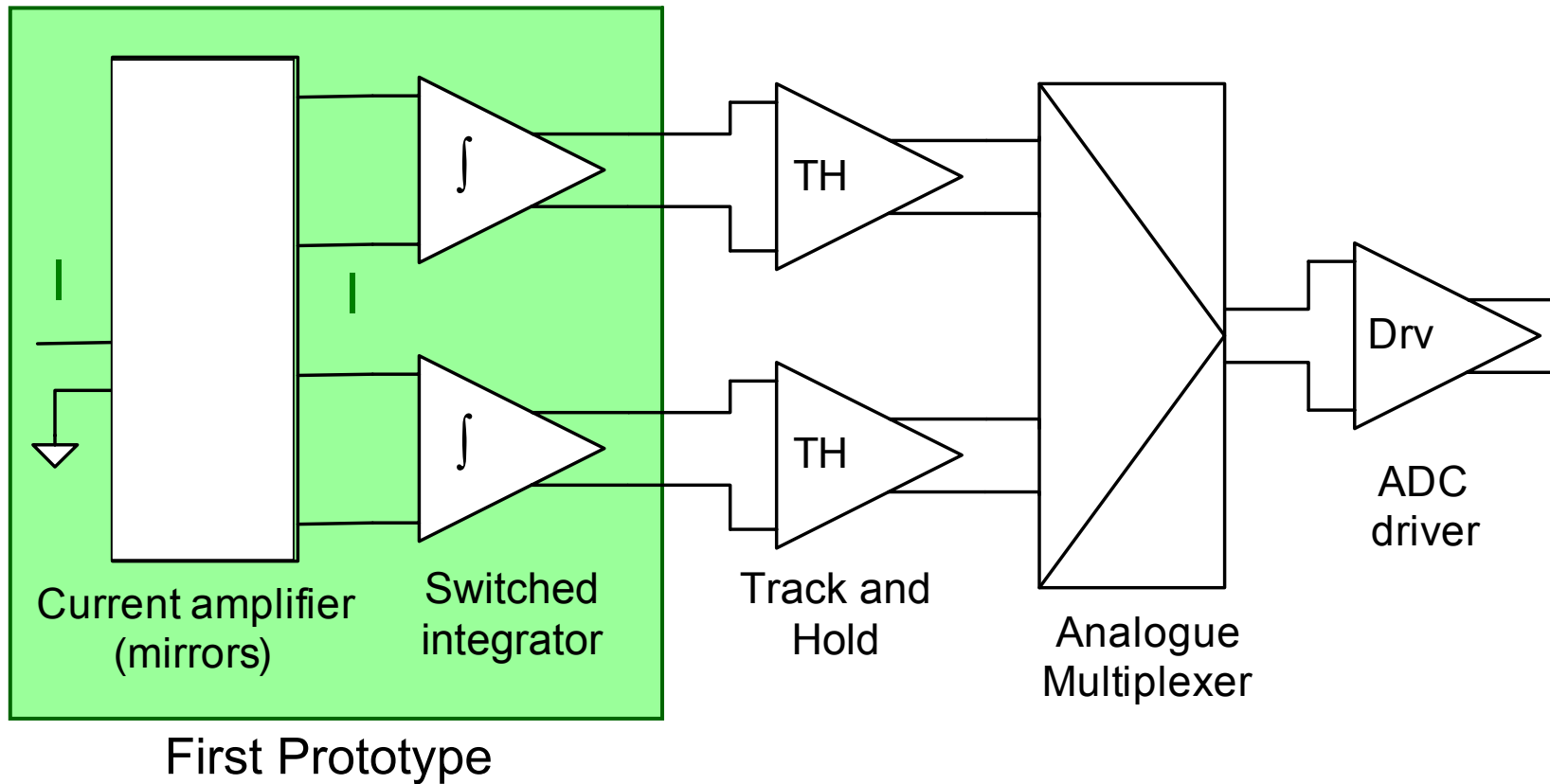
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Calorimeter upgrade meeting – CERN – July 22nd 2011

1. First prototype
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 - ii. Test set-up
 - iii. Offset
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 - v. Input impedance
 - vi. Linearity
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 - viii. Characterization of preamp
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 - i. What is new
 - ii. Flatness: clock jitter vs input signal
3. Summary

First prototype

- ECAL analogue FE IC: channel architecture



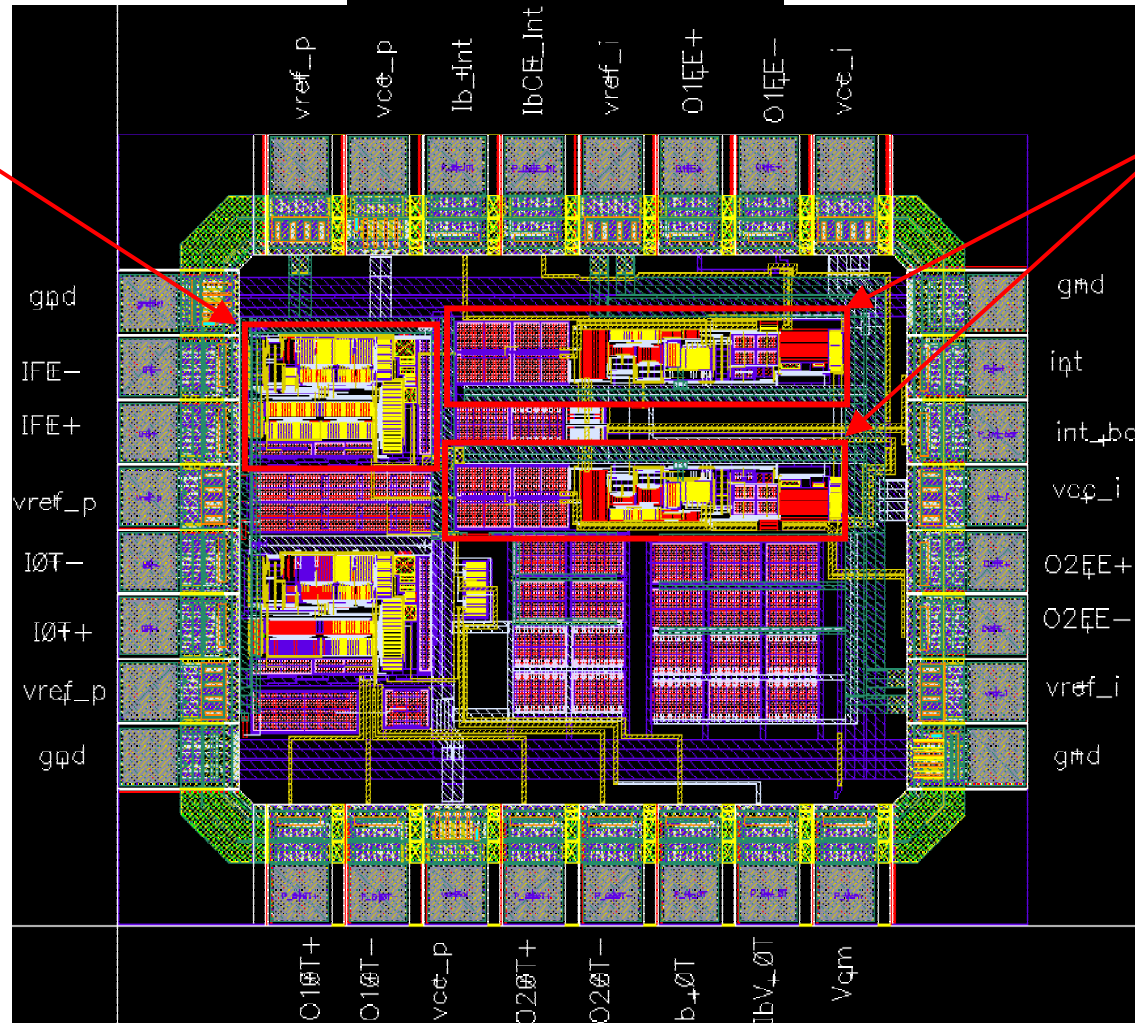
First prototype

- ICECAL chip

SiGe BiCMOS 0.35um
AMS 2 mm²
Submitted: June 7th 2010

Current preamp

Integrators



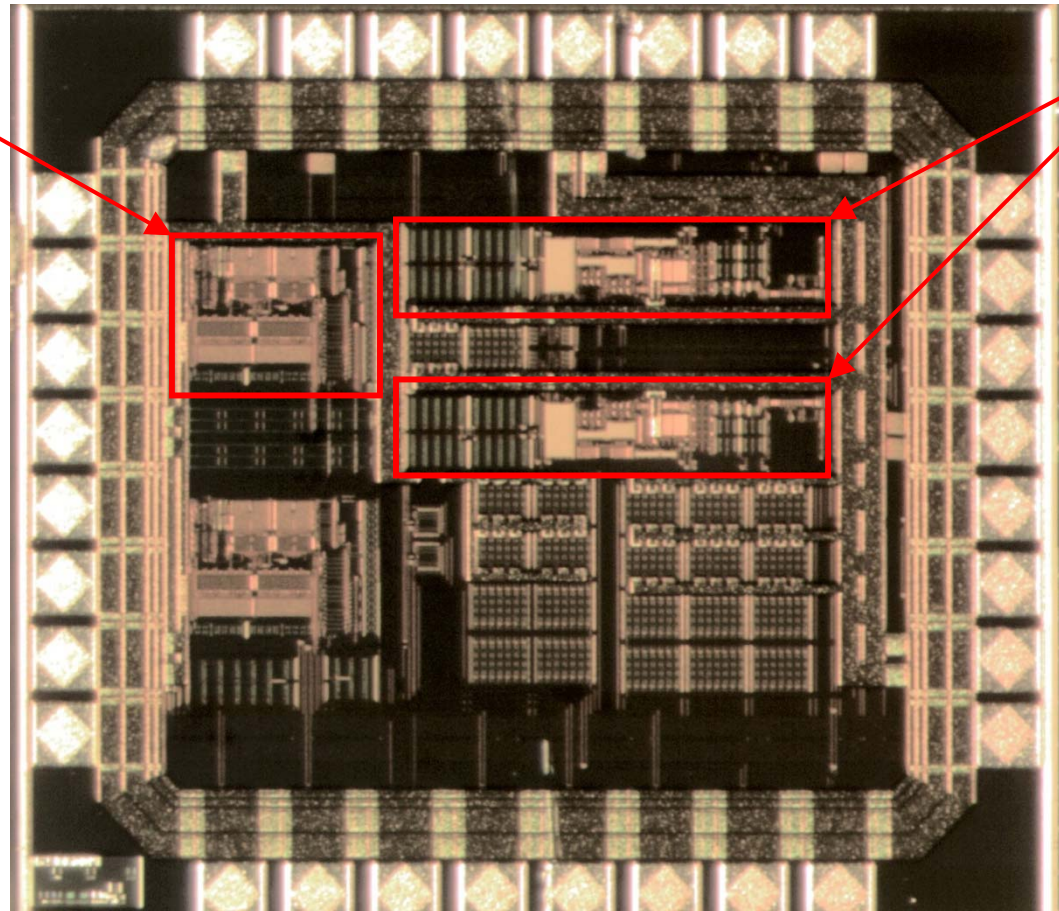
First prototype

- ICECAL chip

SiGe BiCMOS 0.35um
AMS 2 mm²
Received: October 2010
12 chips

Current preamp

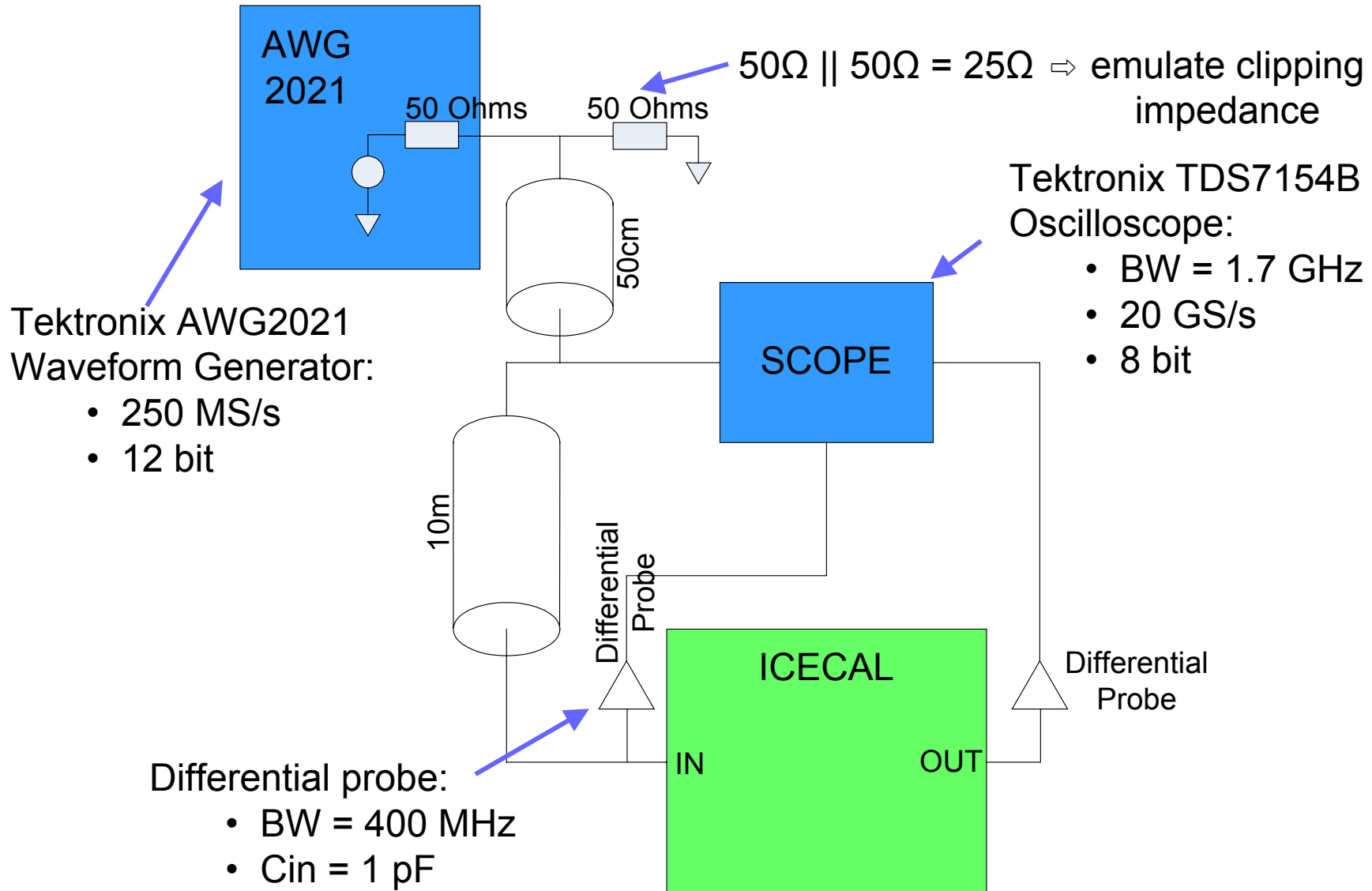
Integrators



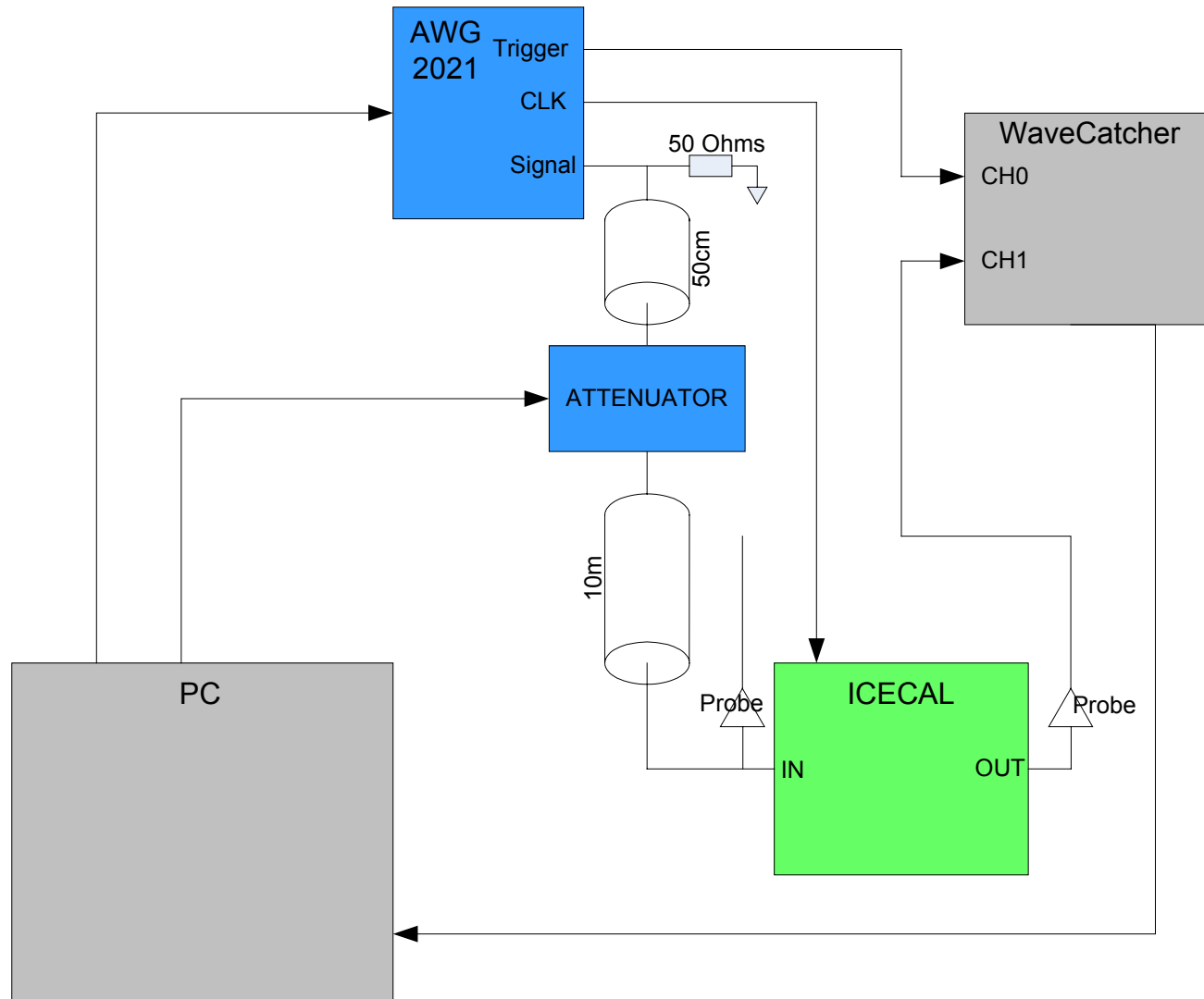
Key tests on the first prototype

- The purpose of this prototype is to test key points of a novel circuit idea:
 - Input impedance control by current feedback
 - Low noise performance
 - Dynamic range:
 - Linearity
- Also, to test critical aspects of a switched solution:
 - Offset between subchannels
 - Noise
 - “Flatness” of the integrator output
 - Effect of the clock jitter versus signal

Test set-up

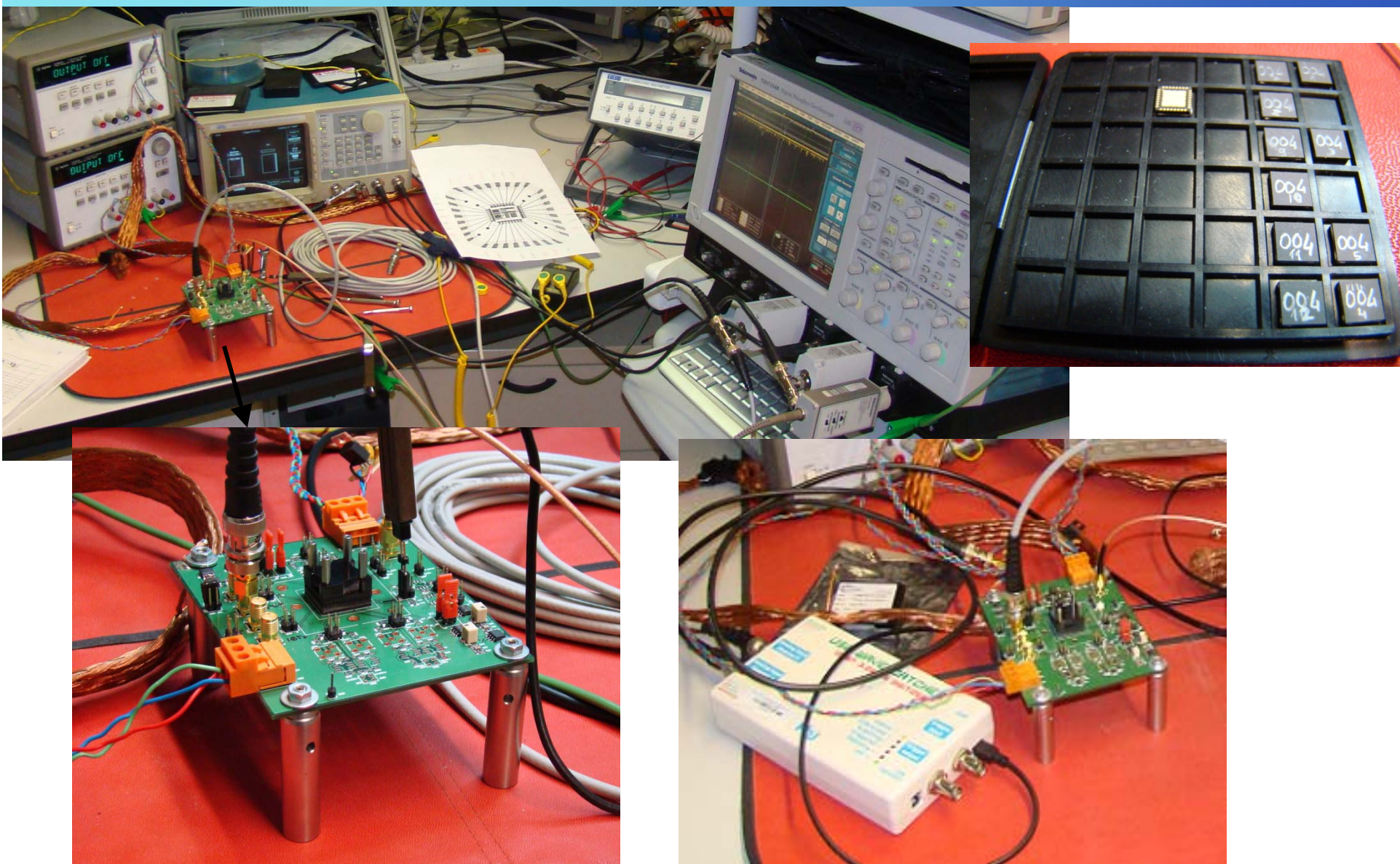


Test set-up: linearity



- **Attenuator:**
 - Better linearity than AWG (<1%)
 - No need for timing corrections
- **WaveCatcher:**
 - Better linearity than oscilloscope
- **PC:**
 - Automated system

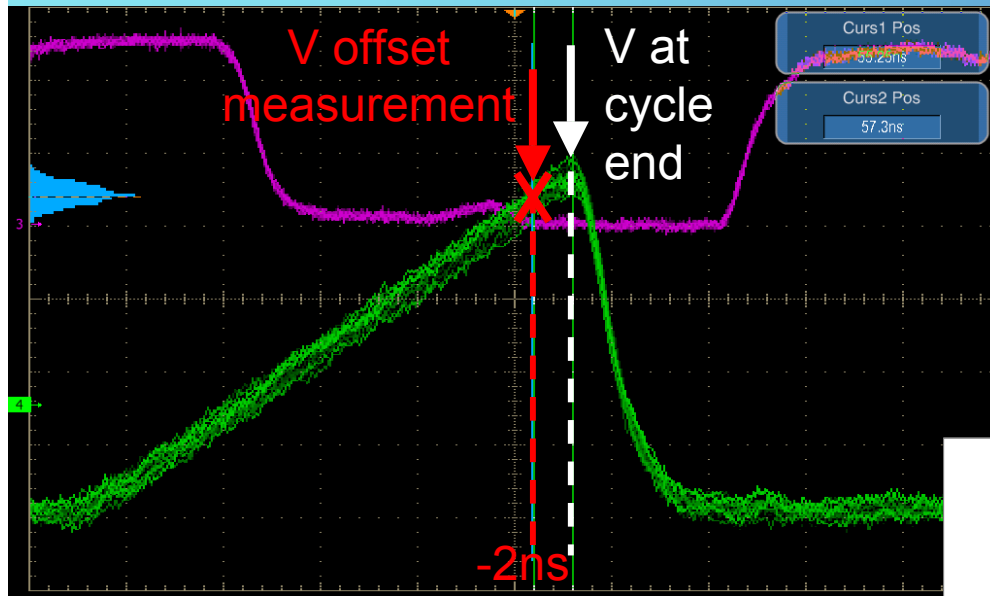
Test set-up



22nd July 2011

LHCb Upgrade

First Prototype: Offset

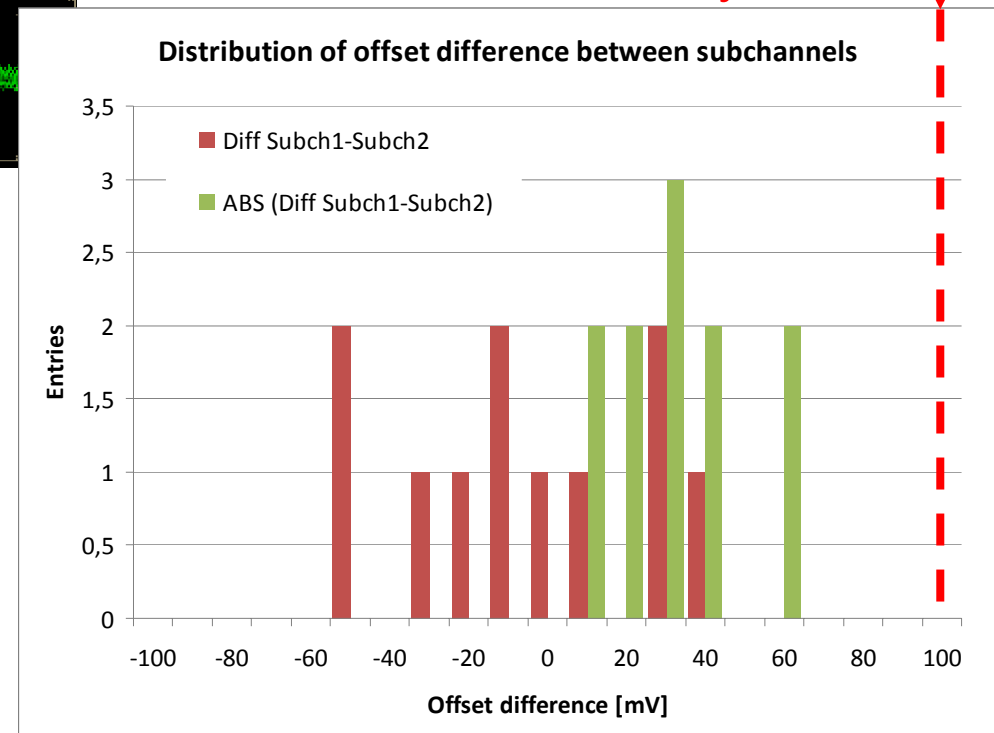


Offset measurement:

Preamp current offset is integrated
=> Offset at output

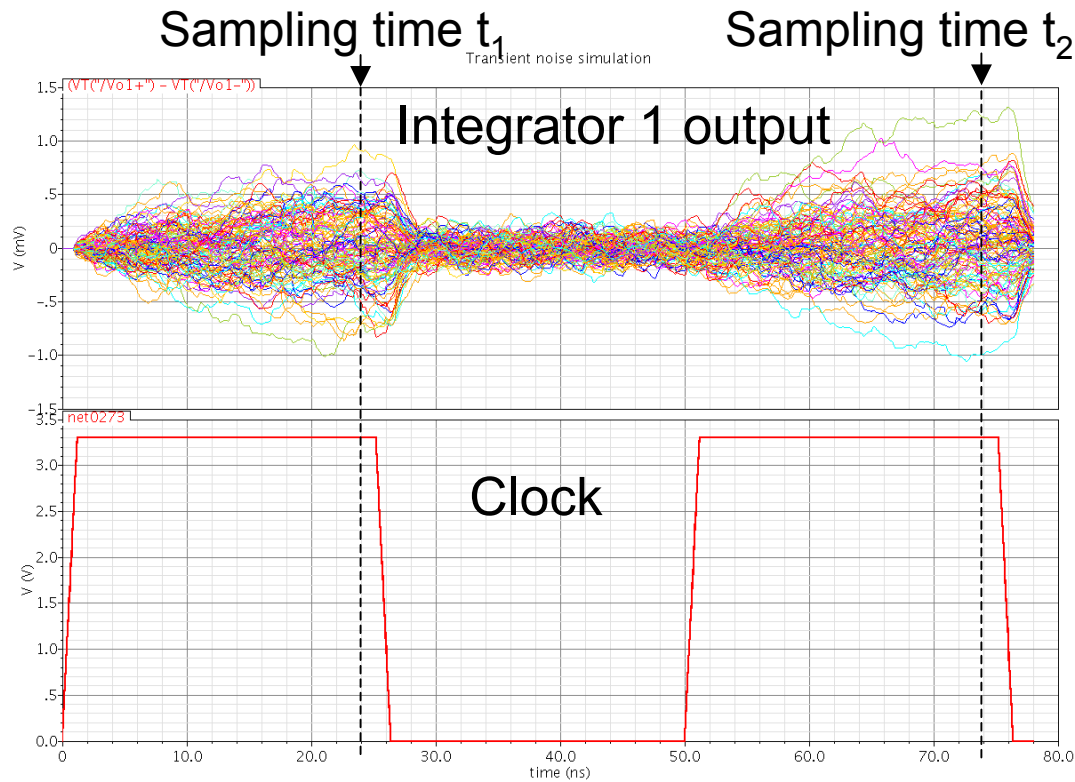
5 % of dynamics

- With AC coupling between ICECAL and ADC what really matters is the difference between the offset of the 2 subchannels
- Well below the 5 % of the full scale range (2 V)

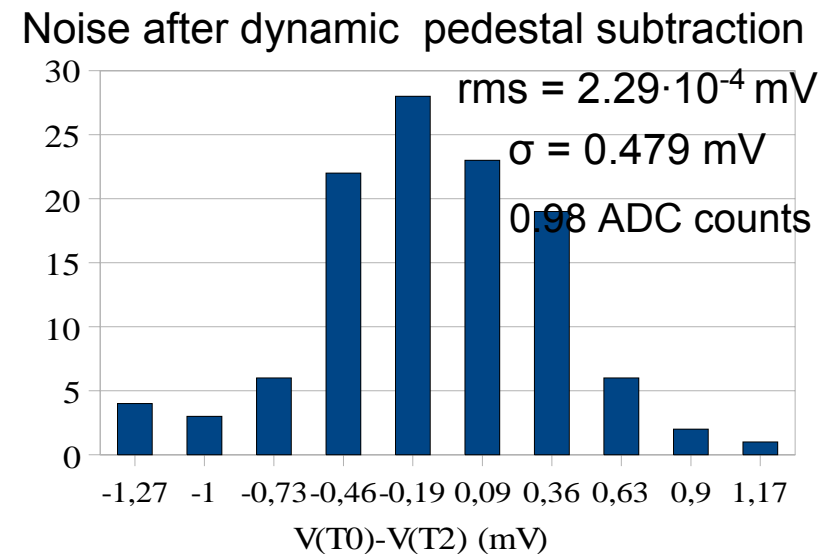
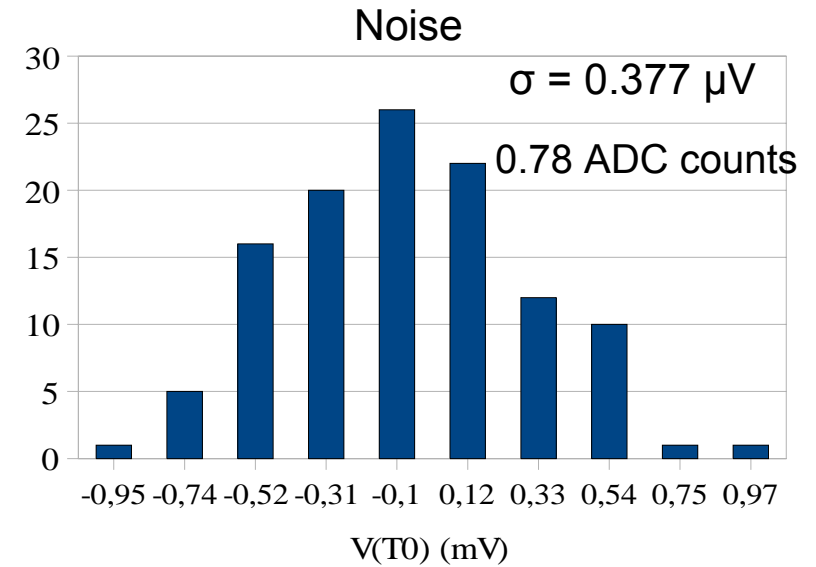


Noise: simulation

- Transient noise analysis

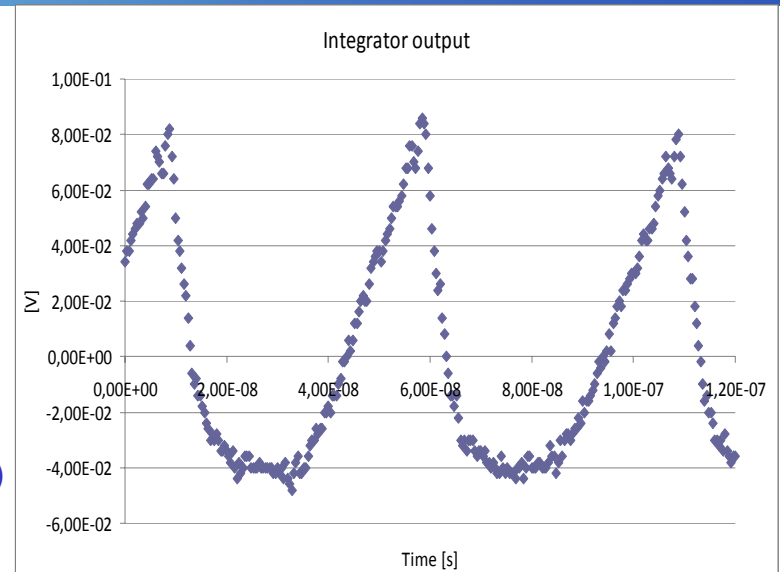


- Correlated sampling: distribution of $V(t_1) - V(t_2)$ to remove LF noise

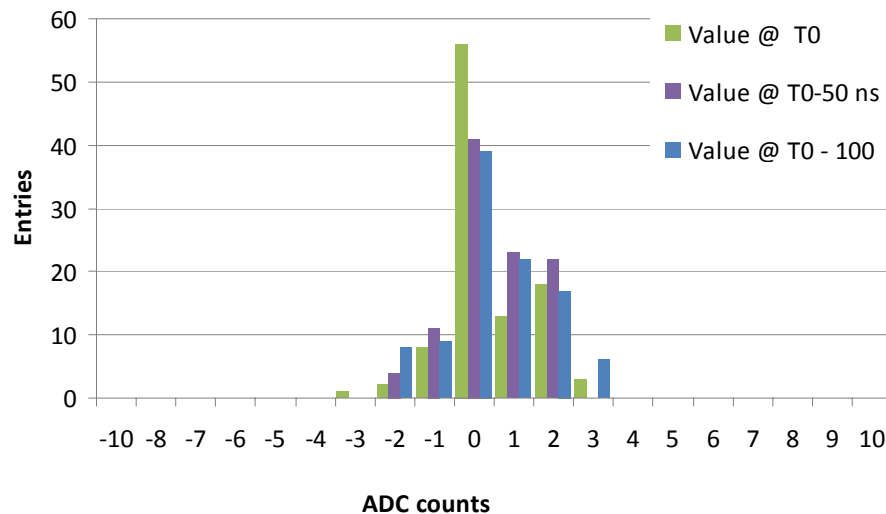


Noise

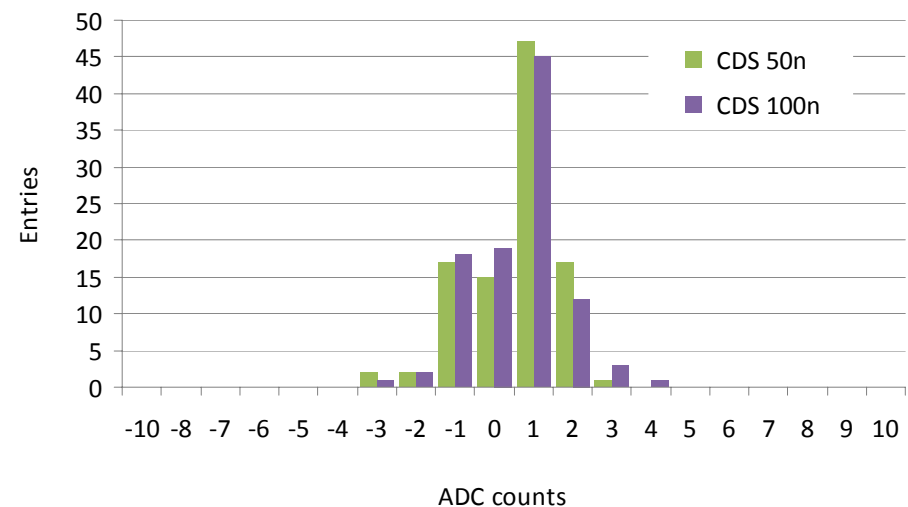
- The noise:
 - Generate a histogram of the voltage value by the end of the cycle (from 100 waveforms).
 - Gaussian fit => standard deviation
- Correlated Double Sampling (CDS) ↔ dynamic pedestal subtraction:
 - LF pick-up noise at measurements (chip connection/socket)
 - without CDS: 1.8 ADC counts
 - with CDS: 1.2 ADC counts (≈1 ADC count from simulations)



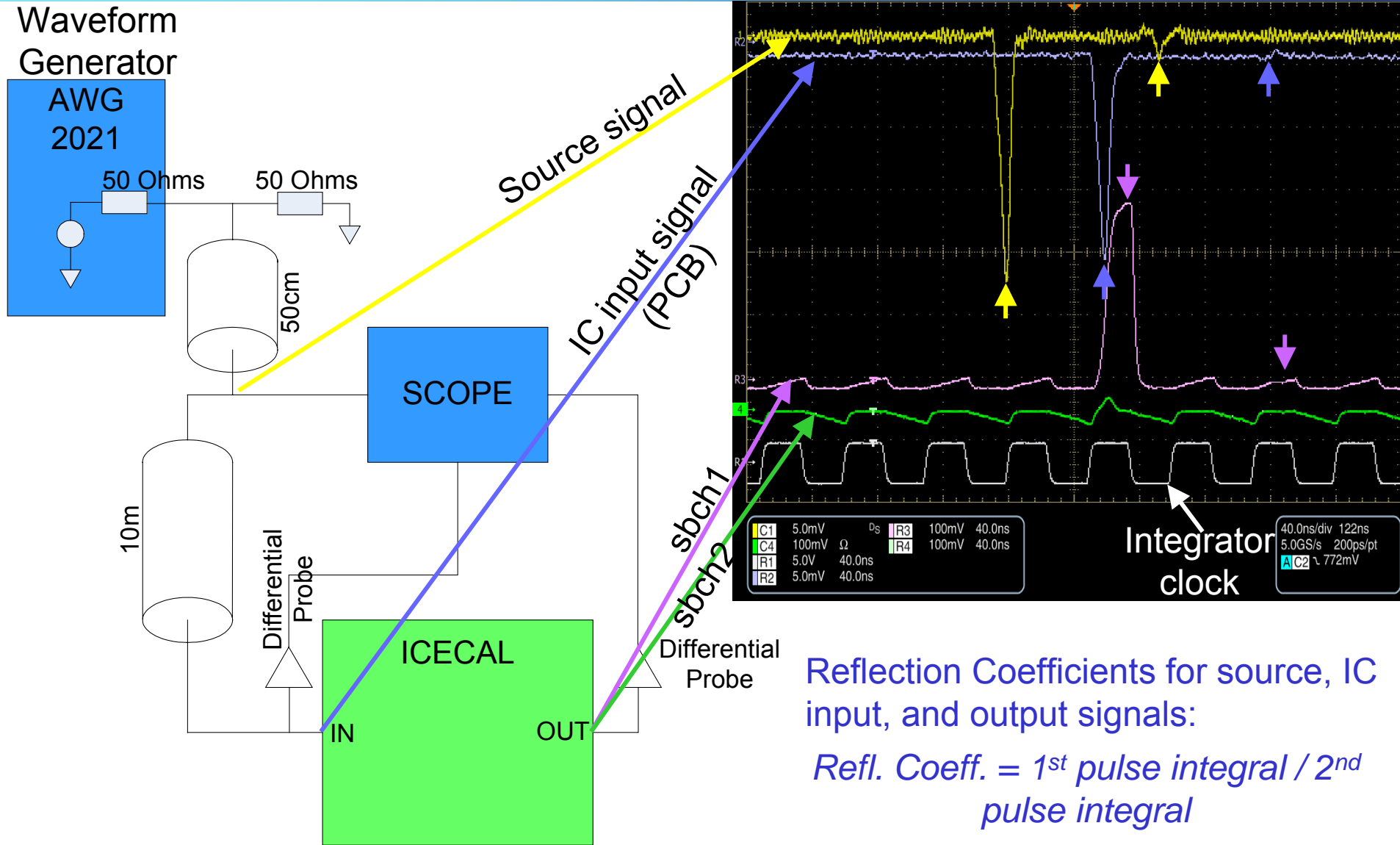
Output fluctuation at different sampling times



Output fluctuation sampled with dynamic pedestal subtraction



Input impedance

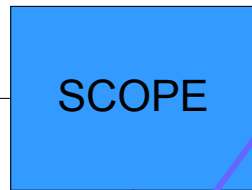
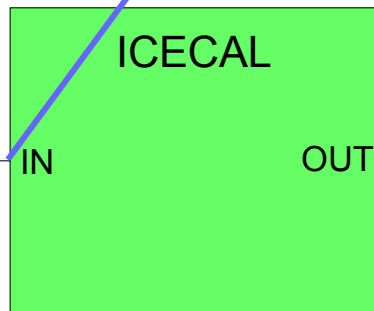
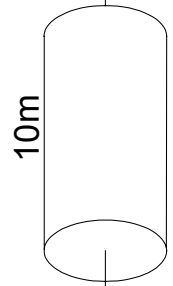
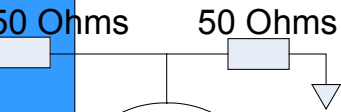
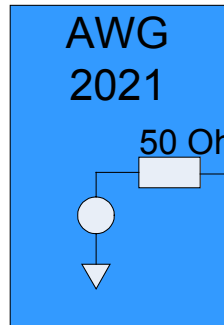


Reflection Coefficients for source, IC input, and output signals:

$$\text{Refl. Coeff.} = \frac{1^{\text{st}} \text{ pulse integral}}{2^{\text{nd}} \text{ pulse integral}}$$

Input impedance

Waveform Generator



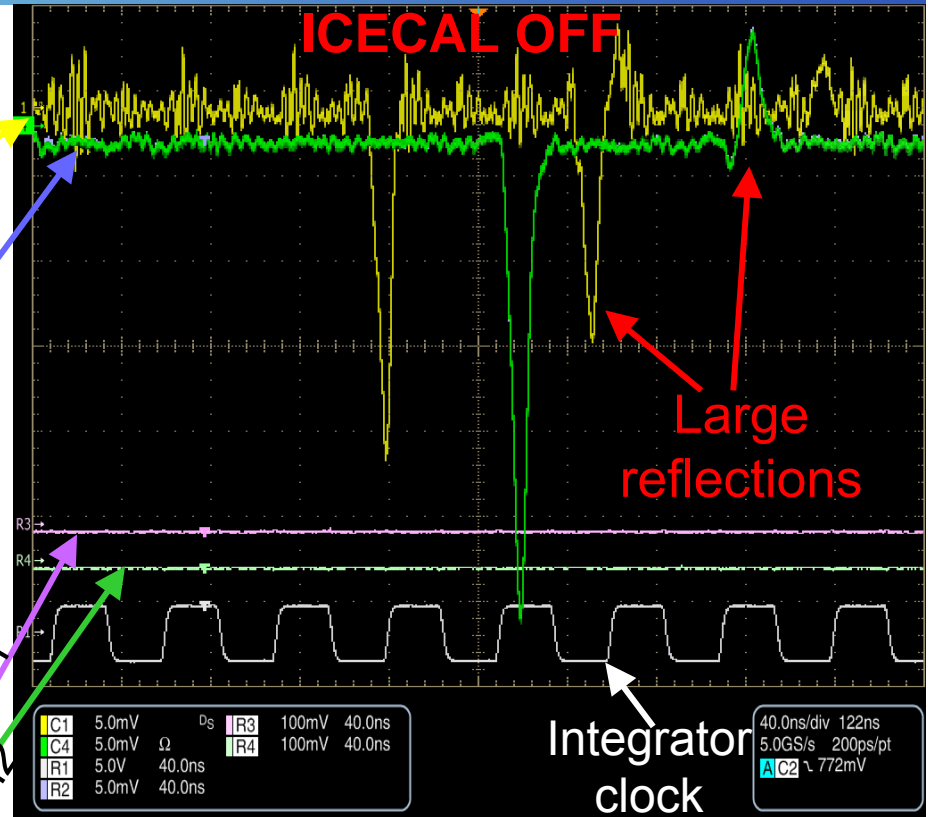
Source signal

IC input signal (PCB)

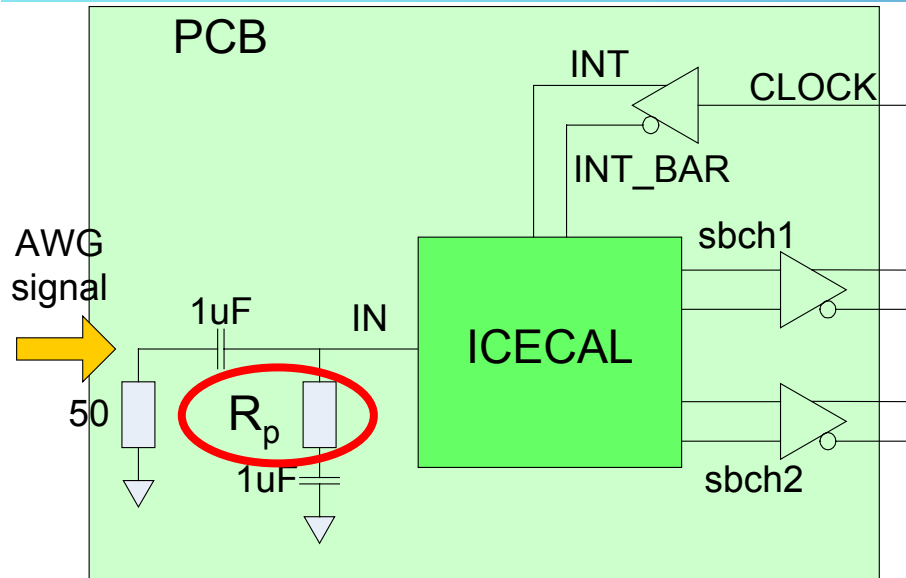
sbch1

sbch2

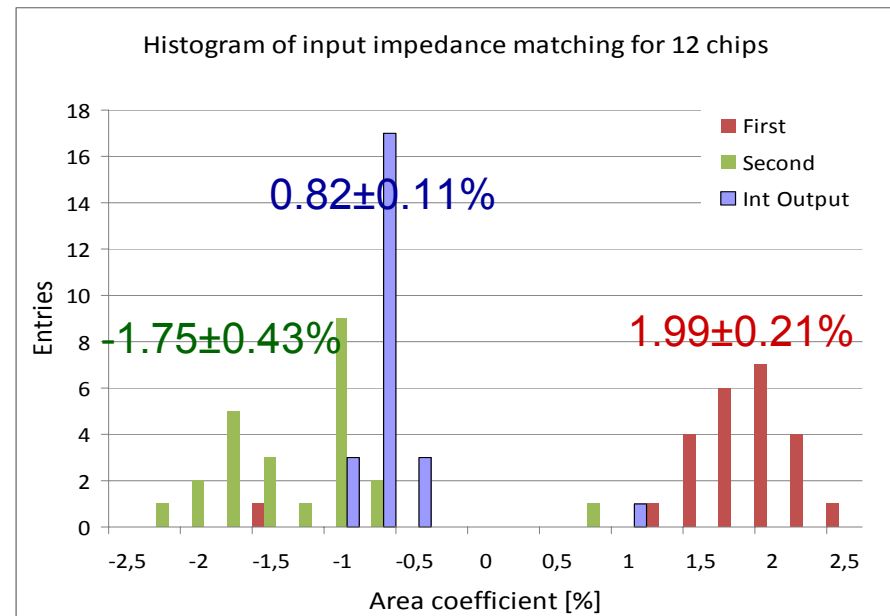
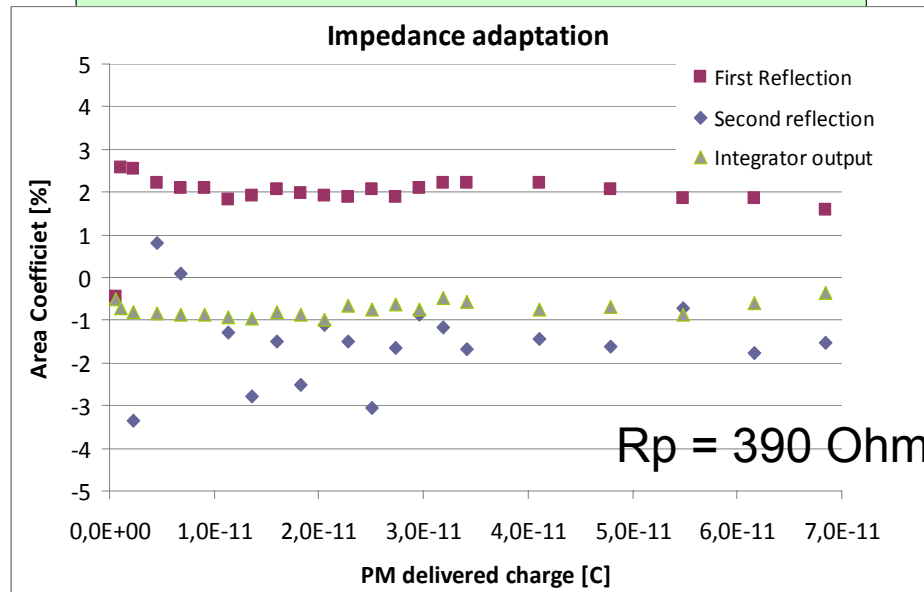
Differential Probe



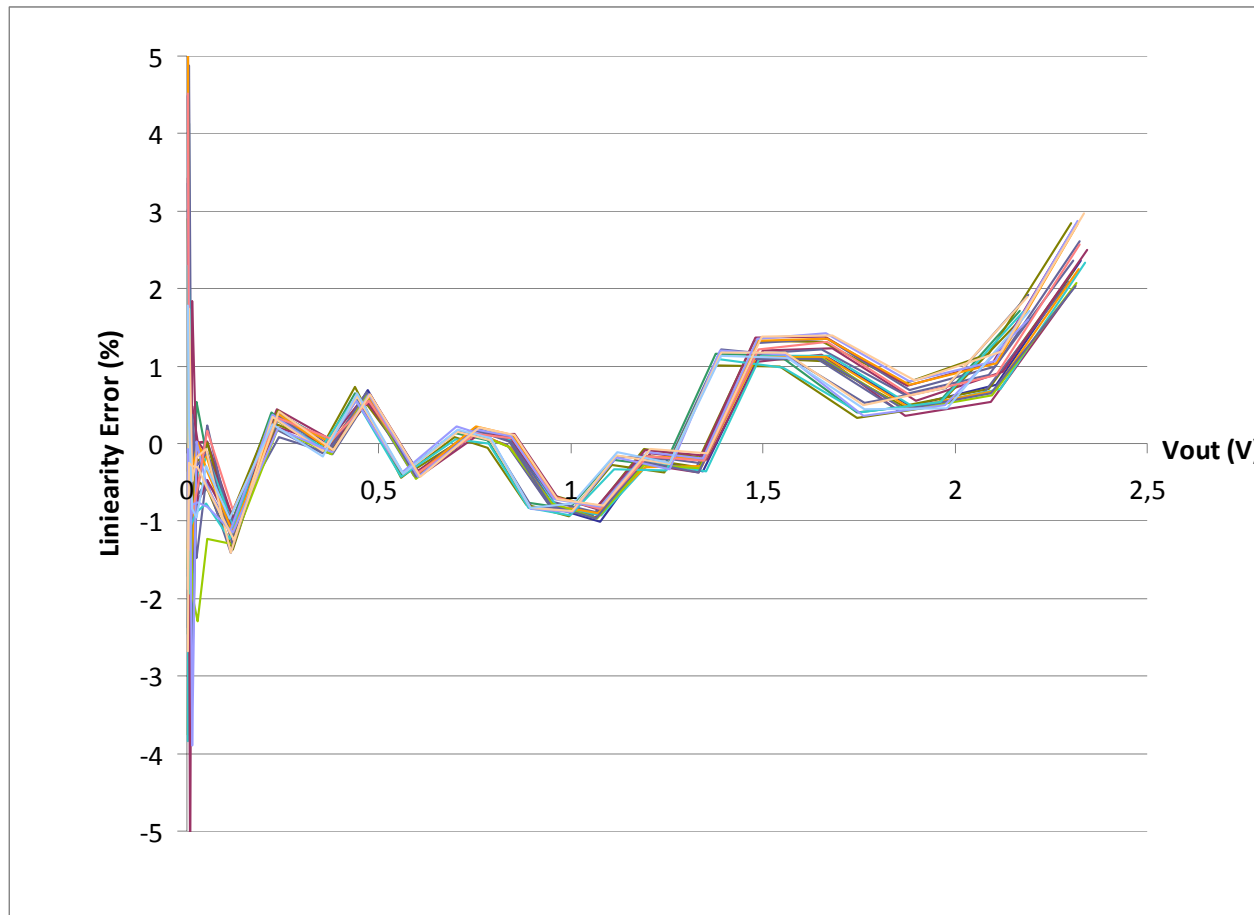
Input impedance



- PCB input circuit with AC coupling with R_p :
 - Z_{in} a little higher than 50Ω
 - R_p used to fine tune Z_{in}
 - Optimal R_p is between 360 and 390Ω
- Dynamic variation of input impedance is $\ll 1\%$ for full dynamic (50 pC)
- Measurement error for second reflection is quite high for low amplitudes (diff probe noise)
- Low Refl. Coef. dispersion $< 0.5\%$



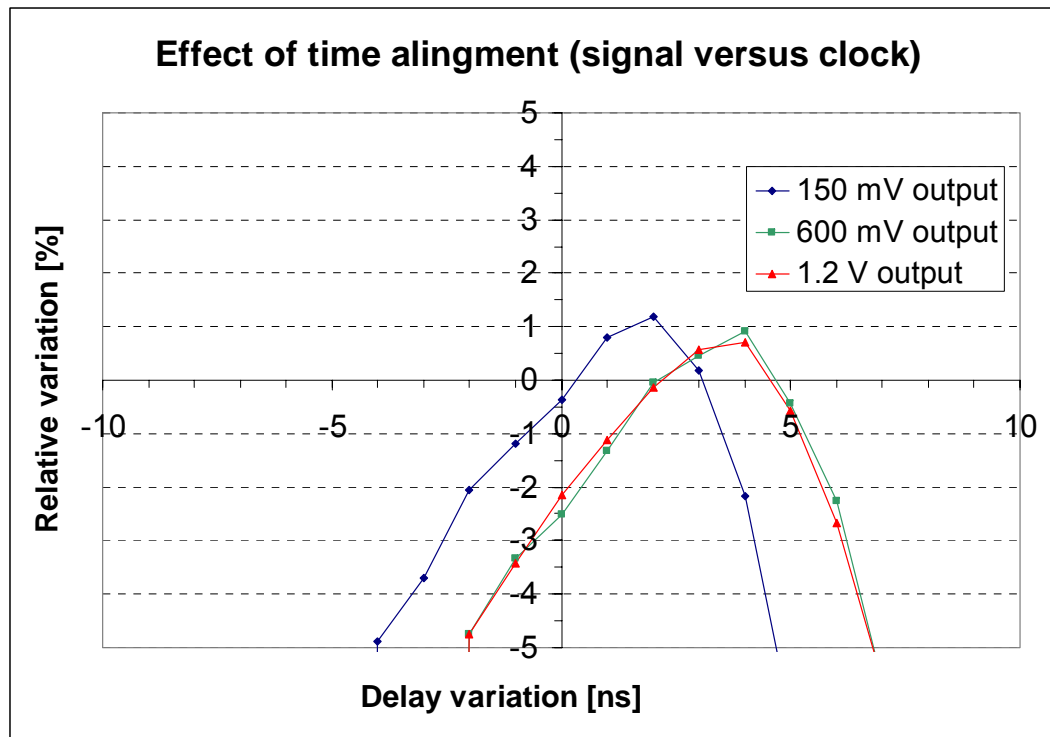
Linearity



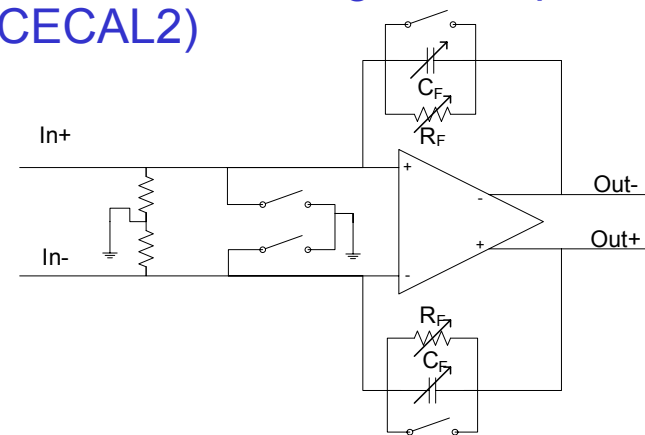
- Relative linearity error $< 1\%$ for the full range (2V)
- Error is large for very low amplitude values
- Attenuator and WaveCatcher offer better linearity but the differential probe may need calibration

Plateau at the integrator output

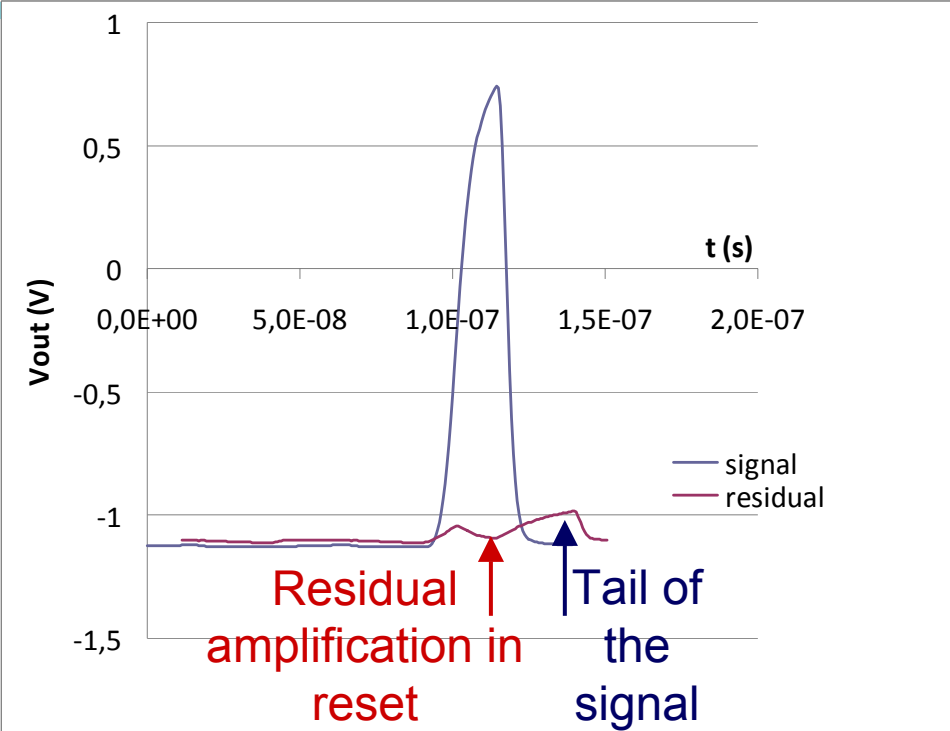
- Due to clock jitter, the signal at the output must be stable (<1%) for 4 ns.
- Input signal AWG generated similar to clipped.
- Method:
 - Delay clock signal in 1ns increments
 - Use LEMO cable



- The output variation is smaller than 1% for about 3 ns delay variation
 - Consistent for different signal amplitudes
- Can be improved using a resistor in parallel to the integrator capacitor (ICECAL2)

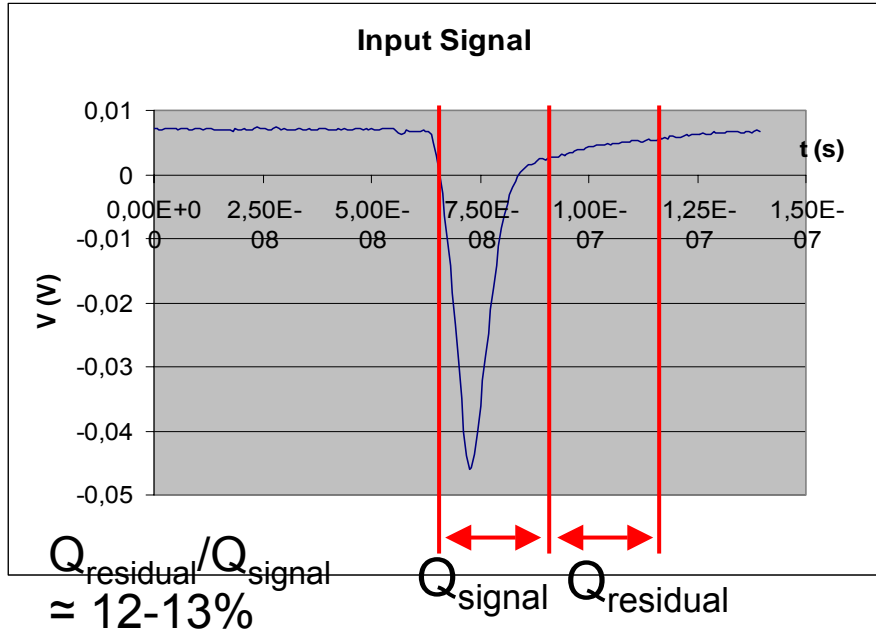


Residual Amplification (switch ON resistance)



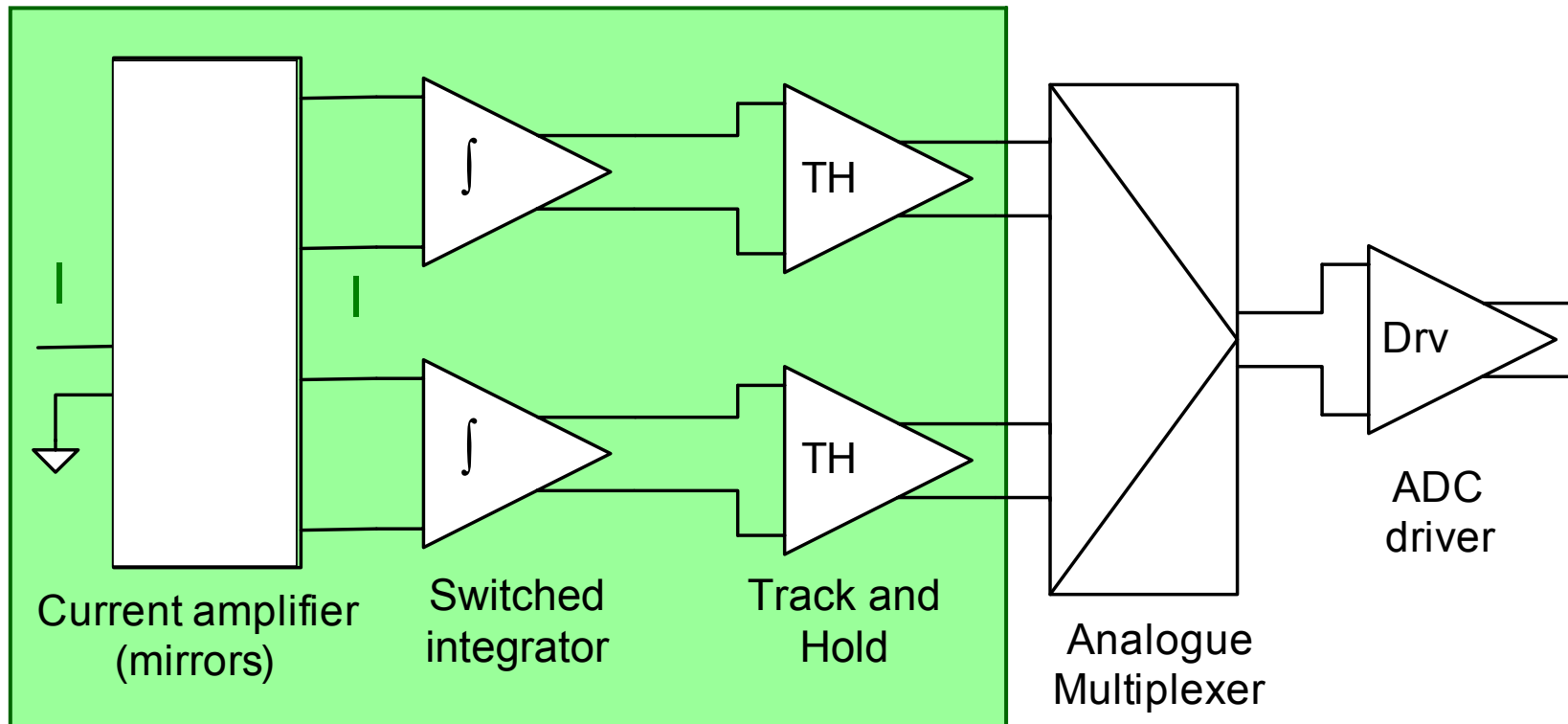
- The residual amplification in reset is 2% of the main signal
- Effect of the tail of the signal:
 - Caused by the signal tail; due to not perfect clipping
 - Measured 12% of the main signal

- Measure at 2 points after cycle with main signal:
 - Just after reset period (beginning of integration period)
 - End of integration period (effects of the tail of the signal)
 - Clipping is not perfect
 - => small signal tail



Second Prototype

ECAL analogue FE IC: channel architecture



Second Prototype:
ICECAL2

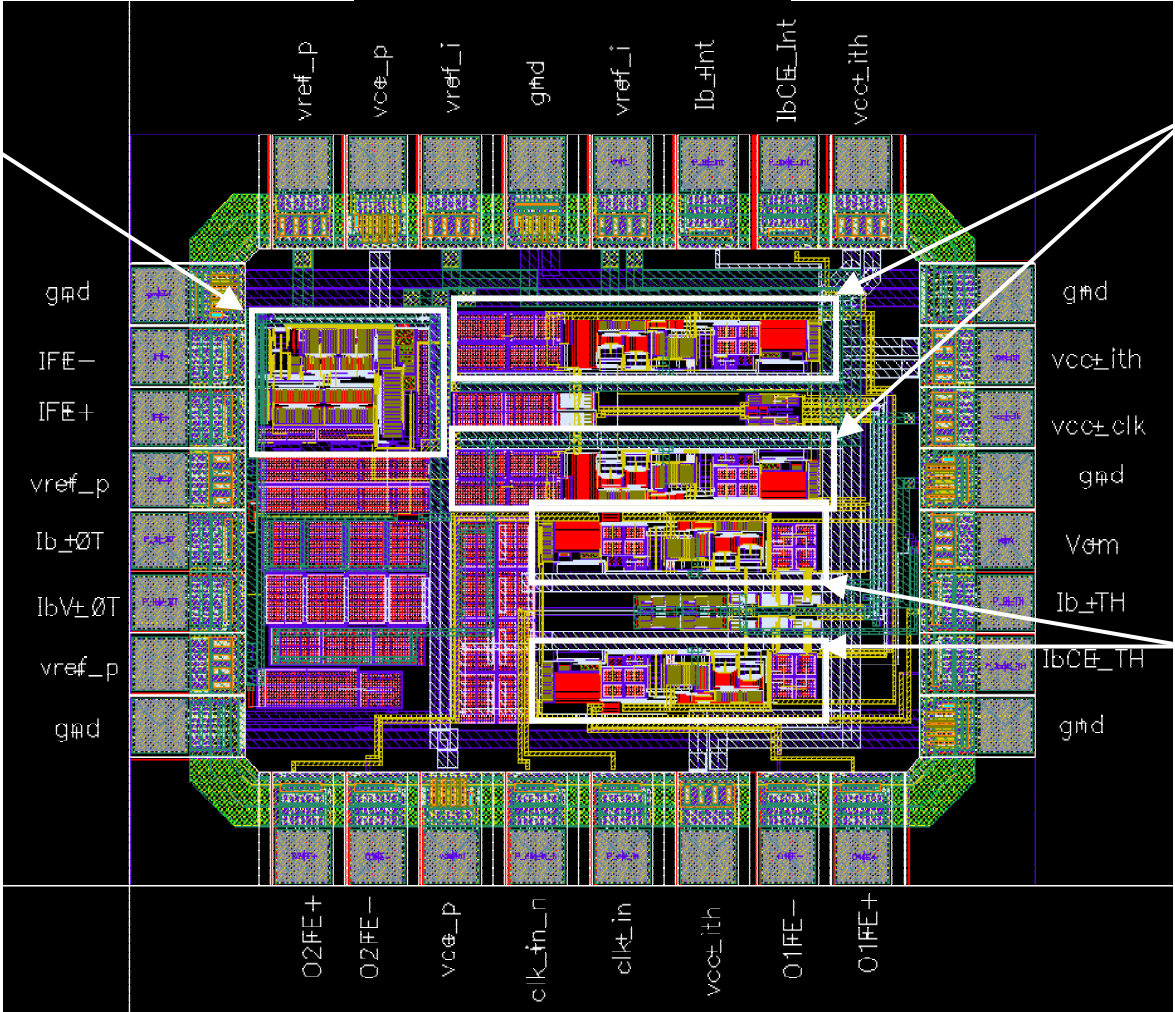
Second Prototype

ICECAL2 chip

SiGe BiCMOS 0.35um
 AMS 2 mm²
 Submitted: June 6th 2011

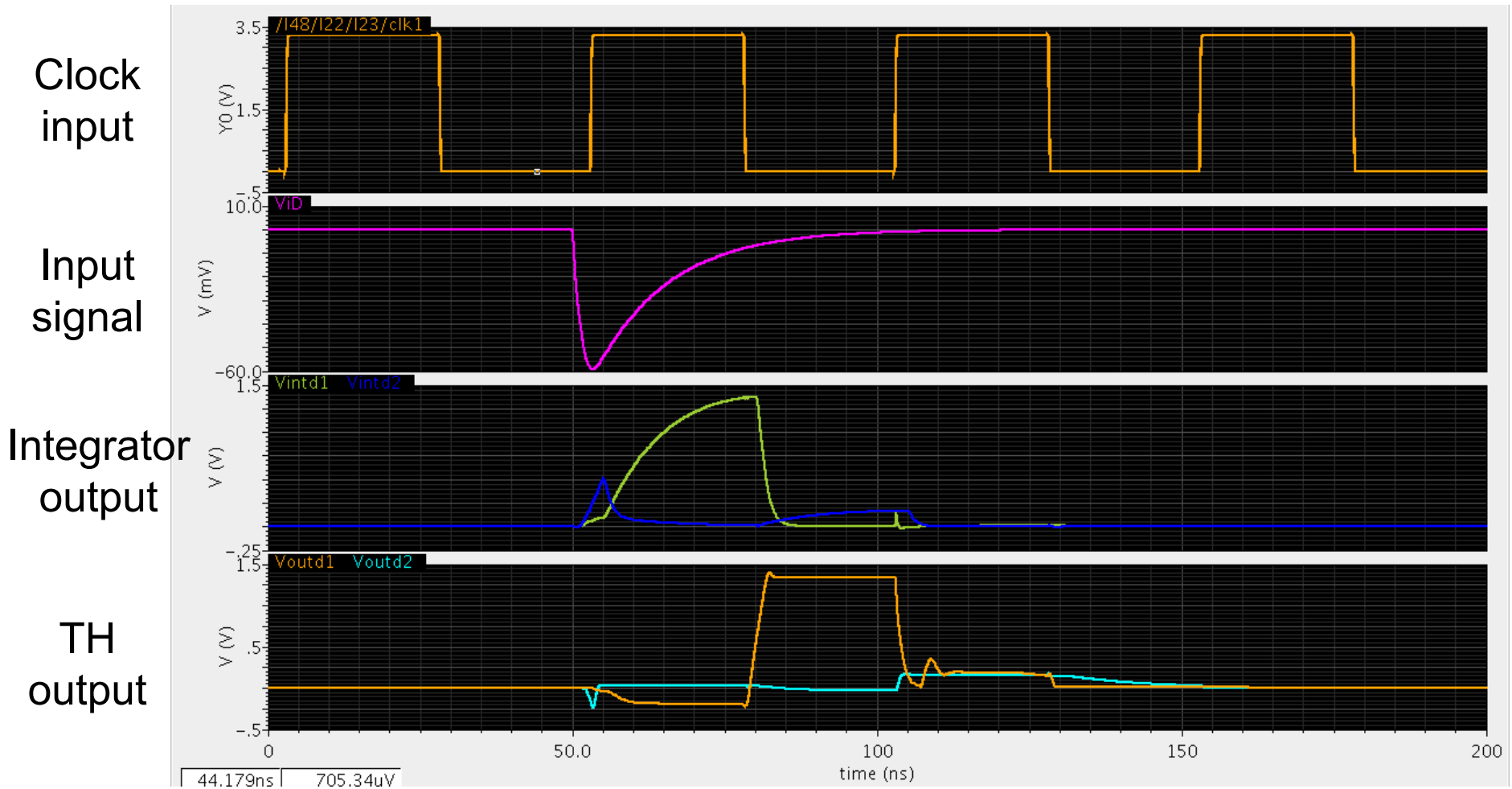
Current preamp

Integrators



Track-and-Hold

Second Prototype



Summary

- Measurements of the first prototype of the input stage (preamp+integrator) are about finished
 - Principle is ok
 - Good results with 12 chips statistics
 - Need to study the effect of bias (op. point) variation
- A second prototype was submitted in June
 - It includes: preamp + integrator + track-and-hold
 - Added a feedback resistor to improve the integrator output stability
- We are preparing a new set-up: AUTOMATIZED IN CAT
 - Analog mezzanine including ICECAL+ADC
 - Calibrated and programmable attenuators
 - 12 bit 500 MHz (3 GS/s) DAQ: WaveCatcher

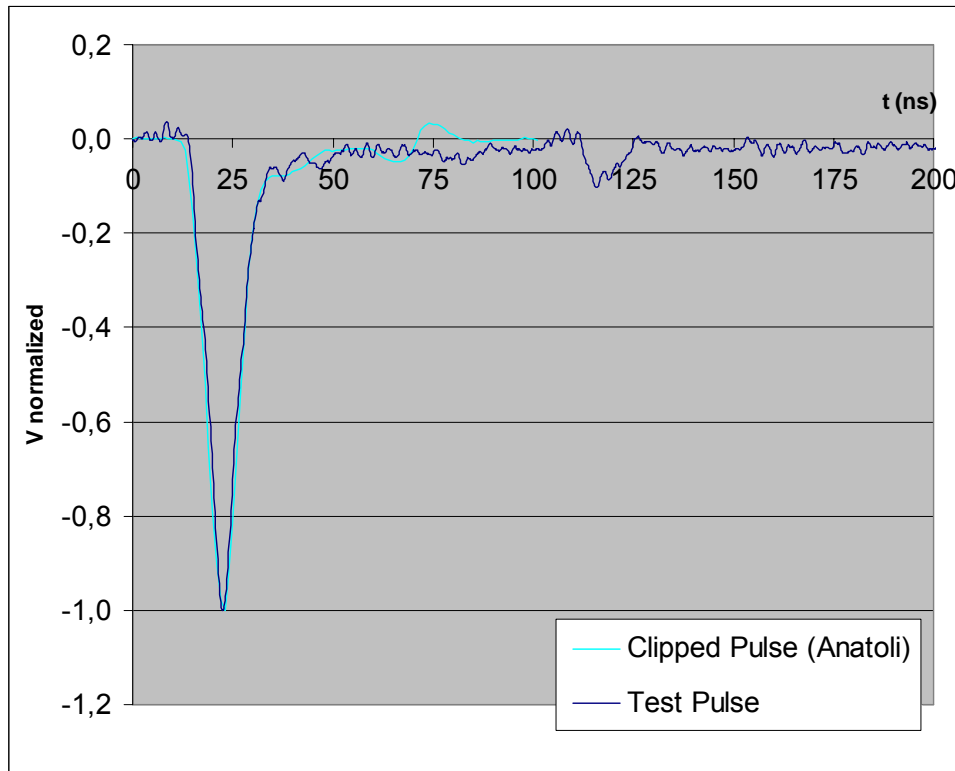
Back-up:



Test set-up



Waveform Generator signal vs. Measured clipped signal (Anatoli)



Fast pulse (no tail) to measure reflections

